

Dennis Rosario

2624

[illegible]

Class	Subclass	Date	Examiner

(Updated)	DATE	EXMR
(East, all dB)	5/17/07	DR
	(10/4/07)	(DR)
	(12/12/07)	(DR)
IEEE-inspection (near) wafer and threshold # -	5/17/07	DR
IEEE- threshold (near) defect and difference (near) image	10/5/07	DR
IEEE- threshold (near) (upper or lower) and different or subtract #) and defect -	12/12/07	DR